

IRPS 2016

IEEE International Reliability Physics Symposium

Monday Tutorial Presentations

April 18, 2016

TU1-5: Wafer Level Reliability Techniques and Models for Determining FEOL/MEOL/BEOL Mechanisms

TU1-6: FINFET Self-Heating and its Implications on Reliability Evaluations

TU1-7: Fault Isolation and Failure Analysis Techniques

TU2-5: Optimizing VLSI Circuit Reliability through Presilicon Design and Postsilicon Adaptation

TU2-6: Circuit Aging 2 - Measurement Techniques

TU2-7: Reliability Differences Between RF and Power Switching GaN Power Transistors

TU3-5: Concepts for Managing System Behavior in the Presence of Hardware Faults

TU3-6: Soft Errors in Functional and System Safety Standards

TU3-7: ESD and EOS Design and Qualification Methods

